

EUROFINS PRODUCT TESTING SERVICE (SHANGHAI) CO., LTD.

# **EMC TEST- REPORT**

**TEST REPORT NUMBER: EFSH14100895-IE-01-E01** 

**Eurofins** Eurofins Product Testing Service (Shanghai) Co., Ltd. No.395 West Jiangchang Road, Zhabei District, Shanghai, 200436, P.R. China

Phone: +86-21-61819181 Fax: +86-21-61819180 Page 1 of 36



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# 2 General Information

# 2.1 Notes

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The results of this test report relate exclusively to the item tested as specified in chapter "Description of test item" and are not transferable to any other test items.

Eurofins Product Testing Service (Shanghai) is not responsible for any generalisations and conclusions drawn from this report. Any modification of the test item can lead to invalidity of test results and this test report may therefore be not applicable to the modified test item.

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Operator:				/ 1
2014-10-23		Boen Yang	Boa-/	~~
Date	Eurofins-Lab.	Name	Signature	

### Technical responsibility for area of testing:

2014-10-23		Ken Xu	KK	
Date	Eurofins	Name	Signature	



# 2.2 Testing laboratory

#### Eurofins Product Testing Service (Shanghai) Co., Ltd.

No.395 West Jiangchang Road, Zhabei District, Shanghai, 200436, P.R. China Telephone : +86-21-61819181 Telefax : +86-21-61819180

#### CNAS ACCREDITED TESTING LABORATORY CNAS-Registration number: L4679

#### Test location, where different:

Name	: Eurofins Product Testing Service (Shanghai) Co., Ltd.
Address	: No.395 West Jiangchang Road, Zhabei District, Shanghai, 200436, P.R.
	China
Telephone	: +86-21-61819181
Fax	: +86-21-61819180
Subcontractor(Radiated emission a	nd Radiated immunity)
Name	: Quietek Technology(Suzhou) Co., Ltd.
Address	: No.99 Hongye Rd., Suzhou Industrial Park luofeng Hi-Tech
	Development Zone, Suzhou, China
Telephone	: +86-512-62515088
Fax	: +86-512-62515098

All tests were performed by Boen yang at Quietek Technology(Suzhou) Co., Ltd.



# 2.3 Details of approval holder

Name	: Xindao B.V.
Address	: P.O. Box 3082, 2280 GB, Rijswijk, The Netherlands
Telephone	:
Fax	: ./.

# 2.4 Application details

Date of receipt of application	: 2014-10-17
Date of receipt of test item	: 2014-10-17
Date of test	: 2014-10-17 to 2014-10-23

# 2.5 EUT information

Description of test item	: 4600 mAh thin powerbank
Type identification	: P324.75
Brand Name	: ./.
Serial number	: ./.
Power supply	: input:DC5.0V/1.0A; output:DC5.0V/2.1A
Additional information	: The appliance is powerbank.
	Adapter was used for test accessory.

# 2.6 Test standards

Technical standard :

# EN 55022:2010

# EN 55024:2010

# EN 61000-3-2:2006+A1: 2009+ A2: 2009

# EN 61000-3-3:2013



# **3** Technical test

# **3.1** Summary of test results

No deviations from the technical specification(s) were ascertained in the course of the tests performed.	$\boxtimes$
or	
The deviations as specified were ascertained in the course of the tests performed.	

# **3.2** Test environment

Temperature	: 20	 25°C
Relative humidity content	: 30	 60%
Air pressure	: 100	 103kPa



# **3.3** Test equipment utilized

	Mea	surement Equipment	List				
No.NameModelManufacturerCal. due date							
1	EMI test receiver	ESCI 30	R&S	2014-11-28			
2	Loop Antenna	HXYZ 9170	TESEQ	2014-11-28			
3	Single phase Harmonics & Flicker analyser	PACS1	California Instruments	2014-11-28			
4	AC Power Source	50001LX	California Instruments	2014-11-28			
5	Coupling/Decoupling Network	L 801 M2/M3	Luethi	2014-11-28			
6	Ultra Compact Simulator	UCS 500N7	EMTEST	2014-11-28			
7	ESD Simulator	NSG 437	TESEQ	2014-11-28			
8	Current transformer	MC2630	EMTEST	2014-11-28			
9	Motor varies	MV2616	EMTEST	2014-11-28			
10	Continuous wave simulator	CWS500N	EMTEST	2014-11-28			
11	Magnetic field coil	MS100	EMTEST	2014-11-28			
12	Current transformer	MC26100	EMTEST	2014-11-28			
13	Artificial mains	ENV216	R&S	2014-11-28			
14	Shielded Room	4*3*3	Zhong-shuo	2014-11-28			
15	Shielded Room	7*4*3	Zhong-shuo	2014-11-28			
16	EMI Test Receiver	ESCI	R&S	2015-03-28			
17	Bilog Antenna	CBL6112D	Teseq GmbH	2015-10-10			
18	Coaxial Cable	SUCOFLEX 106	Huber+Suhner	2015-03-01			
19	Signal Generator	SML03	R&S	2015-09-16			
20	Power Meter	E4416A	Agilent	2015-09-16			
21	Power Sensor	E9323A	Agilent	2015-09-16			
22	Power Meter	4231A	Boonton	2015-09-16			
23	Power Sensor	51011-EMC	Boonton	2015-09-16			
24	RF Switch	SW1072	MF	N/A			
25	Power Amplifier	CBA9428	Schaffner	NA			
26	Power Amplifier	CBA9413B	Schaffner	NA			
27	Directional Coupler	DC7144A	AR	N/A			
28	Directional Coupler	CHA 9652B	Schaffner	N/A			
29	Electric Field Probe	HI-6105	LINDGREN	2015-02-20			
30	Horn Antenna	AT4002A	AR	N/A			
31	Bilog Antenna	CBL6141A	Schaffner	N/A			
32	Temperature/Humidity Meter	ZC1-2	Zhichen	2015-01-08			
33	Preamplifier	NSP1800-25	Miteq	2015-05-03			
34	Bilog Antenna	CBL6112D	Teseq GmbH	2015-10-10			
35	DRG Horn	3117	ETS-Lindgren	2015-07-16			
36	Coaxial Cable	SUCOFLEX 106	Huber+Suhner	2015-03-01			
37	Coaxial Cable	SUCOFLEX 102	Huber+Suhner	2015-03-01			
38	EMI Receiver	N9038A	Agilent	2015-08-07			



# **3.4** Test results

1st test

test after modification

production test

Test case	Sub clause	Required	Test passed	Test failed
Conducted disturbance at the mains ports	Clause 5.1 of EN 55022			
Conducted disturbance at telecommunication ports	Clause 5.2 of EN 55022			
Radiated disturbance below 1GHz	Clause 6.1 of EN 55022	$\boxtimes$	$\boxtimes$	
Radiated disturbance above 1GHz	Clause 6.2 of EN 55022	$\boxtimes$	$\boxtimes$	
Harmonic Current Emissions	EN 61000-3-2			
Voltage Changes, Voltage Fluctuations and Flicker	EN 61000-3-3	X	X	
Electrostatic Discharge	Clause 4.2.1 of EN 55024	$\boxtimes$	$\boxtimes$	
Electrical Fast Transients	Clause 4.2.2 of EN 55024	$\boxtimes$	$\boxtimes$	
Radio frequency electromagnetic fields	Clause 4.2.3.2 of EN 55024	$\boxtimes$	$\boxtimes$	
Injected currents (RF continues conducted)	Clause 4.2.3.3 of EN 55024			
Power-frequency magnetic fields	Clause 4.2.4 of EN 55024	$\boxtimes$	$\boxtimes$	
Surge immunity	Clause 4.2.5 of EN 55024	$\boxtimes$	$\boxtimes$	
Voltage dips and Interruption	Clause 4.2.6 of EN 55024	$\boxtimes$	$\boxtimes$	

Note 1: The Harmonic Current Emissions was not required as the rated power of EUT was less than 75W. Tests need not be made on equipment which is unlikely to produce significant voltage fluctuations or flicker.



# 4 Emission Test

# 4.1 Conducted Emission

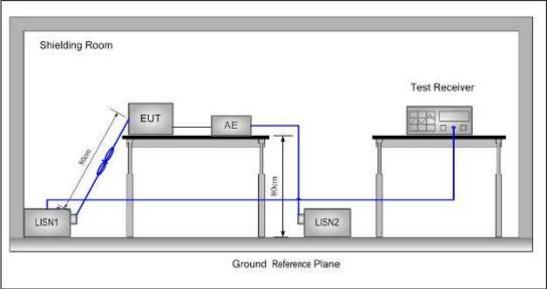
This clause lays down the general requirements for the measurement of disturbance voltage produced at the terminals of apparatus.

# 4.1.1 Limits Class B ITE

Frequency range MHz	At mains terminals dB (µV)							
	Quasi-peak Limit	Average Limit						
0.15 to 0.50	66 to 56	56 to 46						
0.50 to 5	56	46						
5 to 30	60	50						
	NOTE 1 The lower limit shall apply at the transition frequencies.							

NOTE 2 The limit decreases linearly with the logarithm of the frequency in the range 0,15 MHz to 0,50 MHz.

# 4.1.2 Measurement procedure



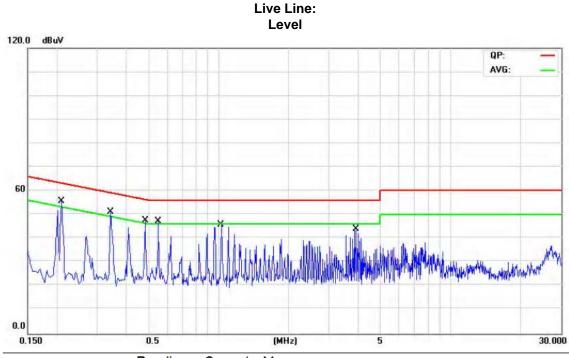
- 1. The mains terminal disturbance voltage was measured with the EUT in a shielded room.
- 2. The EUT was connected to AC power source through a LISN (Line Impedance Stabilization Network) which provides a (50  $\mu$  H + 5  $\Omega$ ) || 50  $\Omega$  linear impedance. The power cables of all other units of the EUT were connected to a second LISN, which was bonded to the ground reference plane in the same way as the LISN for the unit being measured.
- 3. The tabletop EUT was placed upon a non-metallic table 0.8m above the ground reference plane. And for floor-standing arrangement, the EUT was placed on the horizontal ground reference plane, but separated from metallic contact with the ground reference plane by 0.1m of insulation.
- 4. A pre-scan was performed with the peak(PK) and average(AV) detector to find out the maximum emission data plots of the EUT.

# 4.1.3 Measurement uncertainty

Ulab(cond) = 1.8dB at 95% level of confidence, k=2



4.1.4 Results - Measurement Data



No. N	Иk.	Freq.	Reading Level	Correct Factor	Measure- ment	Limit	Over		
		MHz	dBuV	dB	dBu∨	dBu∨	dB	Detector	Comment
1 *	k	0.2100	45.73	9.86	55.59	63.21	-7.62	QP	
2		0.2100	27.25	9.86	37.11	53.21	-16.10	AVG	
3		0.3420	36.59	9.79	46.38	59.15	-12.77	QP	
4		0.3420	21.90	9.79	31.69	49.15	-17.46	AVG	
5		0.4820	32.97	9.72	42.69	56.30	-13.61	QP	
6		0.4820	21.66	9.72	31.38	46.30	-14.92	AVG	
7		0.5500	28.52	9.72	38.24	56.00	-17.76	QP	
8		0.5500	17.79	9.72	27.51	46.00	-18.49	AVG	
9		1.0300	18.32	9.66	27.98	56.00	-28.02	QP	
10		1.0300	8.29	9.66	17.95	46.00	-28.05	AVG	
11		3.9180	9.28	9.94	19.22	56.00	-36.78	QP	
12		3.9180	4.48	9.94	14.42	46.00	-31.58	AVG	



120.0 dBuV QP: AVG: 60 0.0 0.150 0.5 (MHz) 5 30.000 Reading Correct Measure-Limit Over No. Mk. Freq. Level Factor ment MHz dBuV dB dBuV dBuV dB Detector Comment 59.06 -12.58 1 0.3460 36.69 9.79 46.48 QP 2 0.3460 29.68 9.79 39.47 49.06 -9.59 AVG QP 3 0.4900 35.61 9.72 45.33 56.17 -10.84 4 0.4900 29.63 9.72 39.35 46.17 -6.82 AVG 5 47.96 QP 0.9740 38.30 9.66 56.00 -8.04 6 0.9740 31.49 9.66 41.15 46.00 -4.85 AVG 7 56.00 QP 1.1140 37.02 9.68 46.70 -9.30 8 1.1140 31.48 9.68 41.16 46.00 -4.84 AVG 9 2.3660 40.82 9.88 50.70 56.00 -5.30 QP 10 2.3660 32.62 42.50 46.00 9.88 -3.50 AVG 11 3.7540 35.43 9.93 45.36 56.00 -10.64 QP 12 3.7540 46.00 -11.93 AVG 24.14 9.93 34.07

Neutral Line: Level



# 4.2 Radiated disturbance

This clause lays down the general requirements for the measurement of Radiated disturbance produced at the space of apparatus.

# 4.2.1 Limits

Below 1GHz

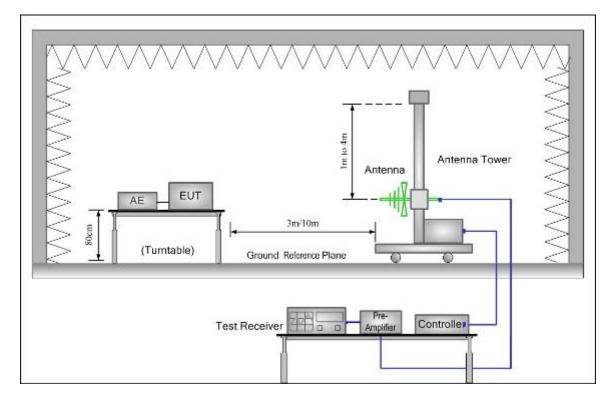
Frequency range	Quasi-peak limits at 3m		
MHz	dB (µV/m)		
30 to 230	40		
230 to 1000	47		

At transitional frequencies the lower limit applies.

Above 1GHz

Frequency range	Average limit	Peaklimit					
GHz	dB(µV/m)	dB(µ∨/m)					
1 to 3	50	70					
3 to 6	54	74					
NOTE The lower limit applies at the transition frequency.							

# 4.2.2 Measurement procedure



1. The radiated emissions test was conducted in a semi-anechoic chamber. The EUT was placed upon a non-metallic table 0.8m above the ground reference plane. And for floor-standing arrangement, the EUT was placed on the horizontal ground reference plane, but separated from metallic contact with the ground reference plane by 0.1m of insulation.

2. Before get the final emission results with quasi-peak(QP) detector, a pre-scan was performed with the peak(PK) detector to find out the maximum emission data plots of the EUT.

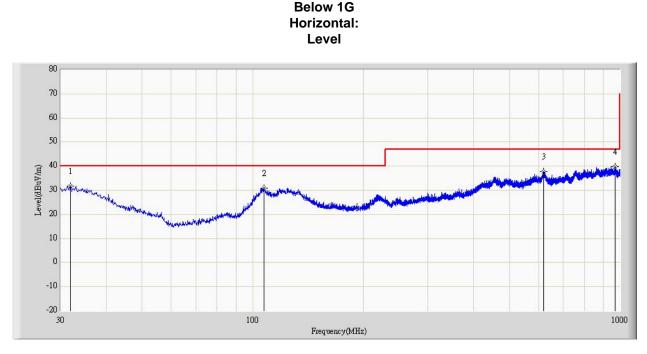


3. The frequencies of maximum emission were determined in the final radiated emissions measurement, the physical arrangement of the test system and associated cabling was varied in order to determine the effect on the EUT's emissions in amplitude, direction and frequency. At each frequency, the EUT was rotated 360°, and the antenna was raised and lowered from 1 to 4 meters in order to determine the maximum disturbance. Measurements were performed for both horizontal and vertical antenna polarization. Test was performed on subcontractor.

# 4.2.3 Measurement uncertainty

Ulab(cond) = 3.9dB at 95% level of confidence , k=2

# 4.2.4 Results



	Frequency (MHz)	Measure Level (dBuV/m)	Reading Level (dBuV)	Over Limit (dB)	Limit (dBuV/m)	Probe (dB/m)	Cable (dB)	Amp (dB)	Ant Pos (cm)	Table Pos (deg)	Туре
	31.819	31.605	5.992	-8.395	40.000	19.154	6.459	0.000	0	0	PK
	107.479	30.968	13.242	-9.032	40.000	10.835	6.891	0.000	0	0	PK
Γ	619.760	37.708	5.034	-9.292	47.000	24.244	8.430	0.000	0	0	PK
	970.172	39.793	5.723	-7.207	47.000	24.900	9.170	0.000	0	0	PK

Note:

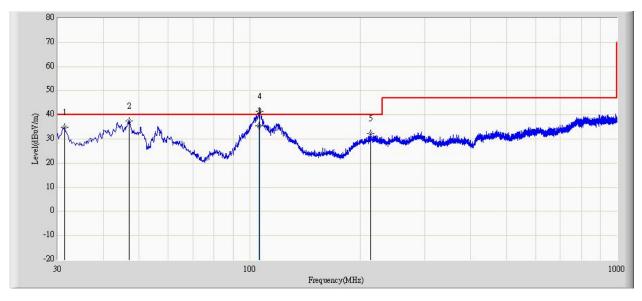
1. All Readings below 1GHz are Quasi-Peak, above are performed with peak and/or average measurements as necessary.

2. Measurement Level = Reading Level + Factor(Probe+Cable-Amp).



Vertical:





Frequency (MHz)	Measure Level (dBuV/m)	Reading Level (dBuV)	Over Limit (dB)	Limit (dBuV/m)	Probe (dB/m)	Cable (dB)	Amp (dB)	Ant Pos (cm)	Table Pos (deg)	Туре
31.334	34.773	10.870	-5.227	40.000	17.449	6.454	0.000	0	0	PK
46.975	37.435	19.084	-2.565	40.000	11.786	6.565	0.000	0	0	PK
105.883	35.521	11.900	-4.479	40.000	16.737	6.885	0.000	100	359	QP
213.087	32.299	8.696	-7.701	40.000	16.293	7.310	0.000	0	0	PK

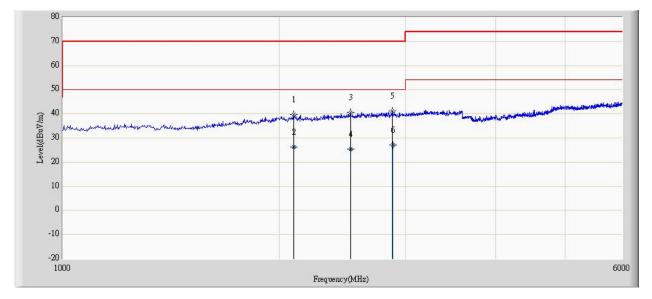
Note:

1. All Readings below 1GHz are Quasi-Peak, above are performed with peak and/or average measurements as necessary.

2. Measurement Level = Reading Level + Factor(Probe+Cable-Amp).



#### Above 1G Horizontal: Level



Frequency (MHz)	Measure Level (dBuV/m)	Reading Level (dBuV)	Over Limit (dB)	Limit (dBuV/m )	Probe (dB/m)	Cable (dB)	Amp (dB)	Ant Pos (cm)	Table Pos (deg)	Туре
2097.500	39.640	39.493	-30.360	70.000	31.544	5.503	36.900	0	0	PK
2098.064	26.251	26.104	-23.749	50.000	31.543	5.504	36.900	200	324	AV
2515.000	40.683	39.289	-29.317	70.000	32.206	6.048	36.860	0	0	PK
2516.024	25.464	24.068	-24.536	50.000	32.206	6.049	36.860	100	152	AV
2877.500	41.138	38.964	-28.862	70.000	32.300	6.530	36.657	0	0	PK
2878.032	27.188	25.014	-22.812	50.000	32.300	6.531	36.657	100	39	AV

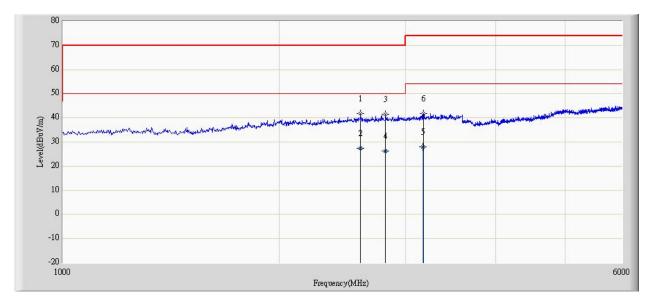
Note:

1. All Readings below 1GHz are Quasi-Peak, above are performed with peak and/or average measurements as necessary.

2. Measurement Level = Reading Level + Factor(Probe+Cable-Amp).



#### Vertical: Level



Frequency	Measure Level	Reading Level	Over	Limit	Probe	Cable	Amp	Ant	Table	Туре
(MHz)	(dBuV/m)	(dBuV)	Limit	(dBuV/m	(dB/m)	(dB)	(dB)	Pos	Pos	
			(dB)	)				(cm)	(deg)	
2597.500	41.768	40.230	-28.232	70.000	32.239	6.149	36.850	0	0	PK
2598.032	27.553	26.014	-22.447	50.000	32.239	6.150	36.850	100	0	AV
2812.500	41.361	39.329	-28.639	70.000	32.300	6.434	36.703	0	0	PK
2813.064	26.130	24.097	-23.870	50.000	32.300	6.435	36.702	200	294	AV
3173.327	28.130	25.102	-25.870	54.000	32.716	6.855	36.543	101	360	AV
3175.000	41.672	38.639	-32.328	74.000	32.720	6.857	36.543	0	0	PK

Note:

1. All Readings below 1GHz are Quasi-Peak, above are performed with peak and/or average measurements as necessary.

2. Measurement Level = Reading Level + Factor(Probe+Cable-Amp).



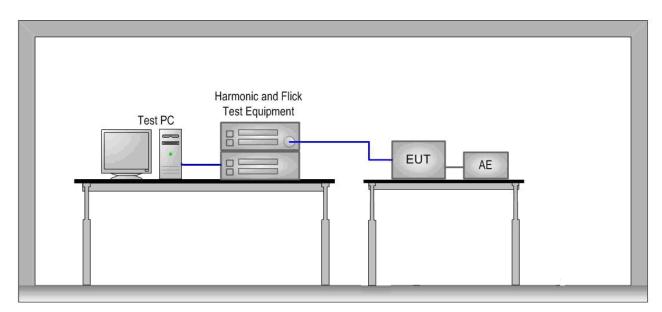
# 4.3 Voltage Changes, Voltage Fluctuations and Flicker

This part is concerned with the limitation of voltage fluctuations and flicker impressed on the public low-voltage system.

# **4.3.1** Limits

Value	Limit
Pst	1,0
Plt	0,65
dt	3,3%
dc	3,3%
dmax	4,0%

# 4.3.2 Measurementest procedure



The equipment under test is placed on a wooden table with a height of 0,8 m in the EMC lab. The voltage changes, fluctuations and flicker were measured at the supply terminals of the EUT.

4.3.3 Results				
Vrms at the end of test (Volt):	229.97			
Highest dt (%):	0.00	Test limit (%):	3.30	Pass
Time(mS) > dt:	0.0	Test limit (mS):	500.0	Pass
Highest dc (%):	0.00	Test limit (%):	3.30	Pass
Highest dmax (%):	0.00	Test limit (%):	4.00	Pass
Highest Pst (10 min. period):	0.064	Test limit:	1.000	Pass
Highest Plt (2 hr. period):	0.028	Test limit:	0.650	Pass



# 5 Immunity Test

# 5.1 Performance Criteria Description in Clause 6 of EN 55024

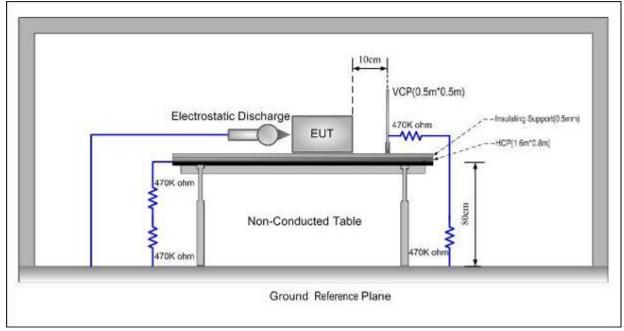
Criterion A:	The equipment shall continue to operate as intended without operator intervention. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer when the equipment is used as intended. The performance level may be replaced by a permissible loss of performance. If the minimum performance level or the permissible performance loss is not specified by the manufacturer, then either of these may be derived from the product description and documentation, and by what the user may reasonably expect from the equipment if used as intended.
Criterion B:	After the test, the equipment shall continue to operate as intended without operator intervention. No degradation of performance or loss of function is allowed, after the application of the phenomena below a performance level specified by the manufacturer, when the equipment is used as intended. The performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is allowed. However, no change of operating state or stored data is allowed to persist after the test. If the minimum performance level (or the permissible performance loss) is not specified by the manufacturer, then either of these may be derived from the product description and documentation, and by what the user may reasonably expect from the equipment if used as intended.
Criterion C:	Loss of function is allowed, provided the function is self-recoverable, or can be restored by the operation of the controls by the user in accordance with the manufacturer's instructions. Functions, and/or information stored in non-volatile memory, or protected by a battery backup, shall not be lost.

The particular performance criteria which are specified in the normative annexes take precedence over the corresponding parts of the general performance criteria. Where particular performance criteria for specific functions are not given, then the general performance criteria shall apply.



# **5.2** Electrostatic discharges

# 5.2.1 Test Procedures



- 1. Contact discharge was applied only to conductive surfaces of the EUT. Air discharge was applied only to non-conducted surfaces of the EUT.
- 2. The EUT was put on a 0.8m high wooden table for table-top equipment or 0.1m high for floor standing equipment standing on the ground reference plane (GRP).
- 3. A horizontal coupling plane(HCP) 1.6m by 0.8m in size was placed on the table, and the EUT with its cables were isolated from the HCP by an insulating support thick than 0.5mm. The VCP 0.5m by 0.5m in size while HCP were constructed from the same material type and thickness as that of the GRP, and connected to the GRP via a 470kΩ resistor at each end. The distance between EUT and any of the other metallic surfaces excepted the GRP, HCP and VCP was greater than 1m.
- 4. During the contact discharges, the tip of the discharge electrode was touching the EUT before the discharge switch is operated. During the air discharges, the round discharge tip of the discharge electrode was approached as fast as possible to touch the EUT. After each discharge, the ESD generator was removed from the EUT, the generator is then retriggered for a new single discharge. For ungrounded product, a discharge cable with two resistances was used after each discharge to remove remnant electrostatic voltage.
- 5. The discharges shall be applied in two ways: a) contact discharges to the conductive surfaces and to coupling planes- The EUT shall be exposed to at least 200 discharges, 100 each at negative and positive polarity, at a minimum of four test points (a minimum of 50 discharges at each point). One of the test points shall be subjected to at least 50 indirect discharges (contact) to the centre of the front edge of the horizontal coupling plane. The remaining three test points shall each receive at least 50 direct contact discharges. If no direct contact test points are available, then at least 200 indirect discharge shall be applied in the indirect mode. Tests shall be performed at a maximum repetition rate of one discharge per second. b) air discharge at slots and apertures, and insulating surfaces: On those parts of the EUT where it is not possible to perform contact discharge testing, the equipment should be investigated to identify user accessible points where breakdown may occur; examples are openings at edges of keys, or in the covers of keyboards and telephone handsets. Such points are tested using the air discharge method. This investigation should be restricted to those areas normally handled by the user. A minimum of 10 single air discharges shall be applied to the selected test point for each such area.



# 5.2.2 Results

Test point	Table (T) Floor (F)	Contact (C) Air (A)	Voltage (kV)	Number of discharge	<b>Polarity</b> (+ / -)	Opinion
Air contact	Т	А	8	20	+ / -	A
Direct contact	Т	С	4	200	+ / -	A
HCP	Т	С	4	200	+ / -	А
VCP	Т	С	4	200	+/-	А

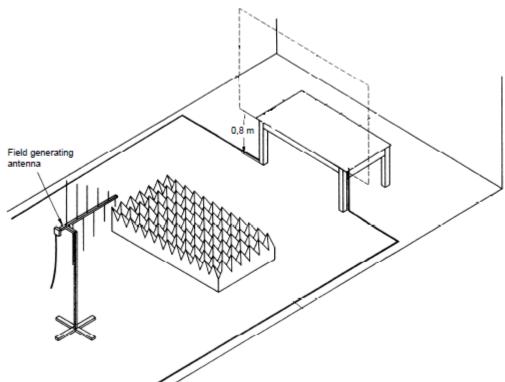
A: no loss of function.

B: the appliance wound not work normally during test, but after test it could recover itself.



# **5.3** Radio frequency electromagnetic fields

# 5.3.1 Measurement procedure



- 1 The EUT was placed on 0.8m high wooden table for table-top equipment. For floor standing equipment, the EUT was placed on a 0.1m high wooden support above the GRP.The tests normally shall be performed with the generating antenna facing each of four sides of the EUT. When equipment can be used in different orientations (e.g. vertical or horizontal) the test shall be performed on all possible sides of the EUT.
- 2 The tests are carried out with a field strength by 3 V/m (measured in the unmodulated field) with amplitude modulated signal by a depth of 80 % by a sinusoidal audio signal of 1 kHz. The logarithmic step was 1% and the dwell time was 3s dependent of the EUT cycle time.
- 3 The EUT shall be positioned so that the four sides of the EUT shall be exposed to the electromagnetic field in sequence. In each position the performance of the EUT will be investigated. In the case where the most sensitive surface side of the EUT is known throughout the frequency range (for example, via preliminary tests), testing may be restricted to that surface side only. Test was performed on subcontractor.

# 5.3.2 Results

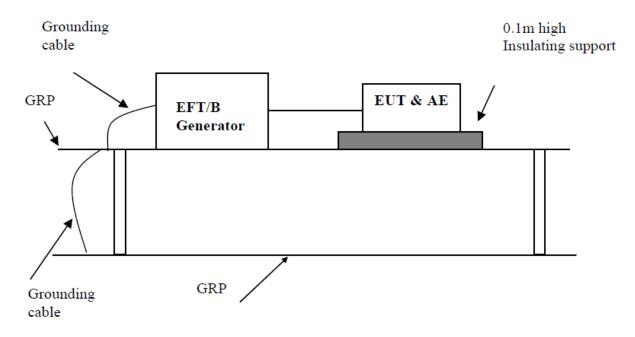
Frequency Range	Voltage(RMS)	Modulation Frequency	Opinion
80M-1GHz	3V/m	1kHz,80%,AM	А

A: no loss of function.



# **5.4** Electrical Fast Transients

# 5.4.1 Measurement procedure



- 1. The EUT was placed on a ground reference plane(GRP) insulated by an insulating support 0,1 m thick and the GRP was placed on a 0.8m high wooden table for table-top equipment. For floor standing equipment, the EUT was placed on a 0.1m high wooden support above the GRP.
- 2. The GRP shall project beyond the EUT and the clamp by at least 0.1m on all sides. The distance between the EUT and any other of the metallic surface except the GRP was greater than 0.5m. All cables to the EUT was placed on the insulation support 0.1m above GRP. Cables not subject to EFT was routed as far as possible from cable under test to minimize the coupling between the cables.
- 3. The length of signal and power cable between the EUT and EFT generator was 0.5m. If the cable is a non-detachable supply cable more than 0.5m, the excess length of this cable shall be folded to avoid a flat coil and situated at a distance of 0.1m above the GRP.

# 5.4.2 Results

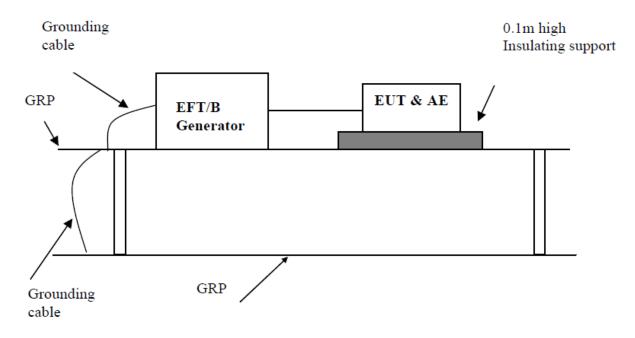
Test port	Voltage (kV)	Polarity (+ / -)	Duration (s or min)	Waveform Tr / Th	Repetition Frequency (kHz)	Opinion
AC power line	1	+	2 min	5/50 ns	5	A
AC power line	1	-	2 min	5/50 ns	5	A

A: no loss of function.



# 5.5 Surge Immunity

# 5.5.1 Measurement procedure



- 1. The EUT was placed on a ground reference plane(GRP) insulated by an insulating support 0,1 m thick and the GRP was placed on a 0.8m high wooden table for table-top equipment. For floor standing equipment, the EUT was placed on a 0.1m high wooden support above the GRP.
- 2. The 1,2/50 µs surge was to be applied to the EUT power supply terminals via the capacitive coupling network .Decoupling networks were required in order to avoid possible adverse effects on equipment not under test that may be powered by the same lines and to provide sufficient decoupling impedance to the surge wave so that the specified wave may be applied on the lines under test.
- 3. Five positive and five negative pulses each at 0°, 90°, 180° and at 270°. Time between successive pulses: 1 min.

Test mode	<b>Polarity</b> (+ / -)	Voltage (kV)	Waveform Tr / Th	Number of pulses	Opinion
Live-Neutral	+	1	1.2/50 µs	5	А
Live-Neutral	-	1	1.2/50 µs	5	А
Live-PE	+	N/A	1.2/50 µs	5	N/A
Live-PE	-	N/A	1.2/50 µs	5	N/A
Neutral-PE	+	N/A	1.2/50 µs	5	N/A
Neutral-PE	-	N/A	1.2/50 µs	5	N/A

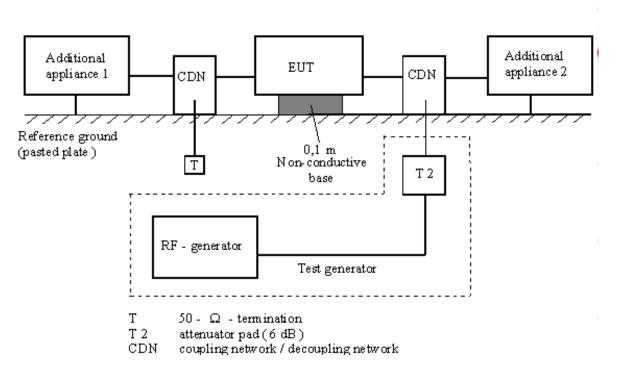
#### 5.5.2 Results

A: no loss of function.



# **5.6** Injected currents(RF continues conducted)

# 5.6.1 Measurement procedure



- 1. The EUT was placed on an insulating support of 0.1m height above a ground reference Plane, arranged and connected to satisfy its functional requirement. All cables exiting the EUT was supported at a height of at least 30 mm above the ground reference plane.
- 2. The coupling and decoupling devices were required, they were located between 0,1 m and 0,3 m from the EUT. This distance was to be measured horizontally from the projection of the EUT on to the ground reference plane to the coupling and decoupling device.
- 3. The frequency range was swept from 150 kHz to 80 MHz, using the signal levels established during the setting process, and with the disturbance signal 80 % amplitude modulated with a 1 kHz sine wave, pausing to adjust the RF signal level or to change coupling devices as necessary. Where the frequency was swept incrementally, the step size do not exceed 1 % of the preceding frequency value. The dwell time of the amplitude modulated carrier at each frequency was not less than the time necessary for the EUT to be exercised and to respond, and was not less than 3s.

# 5.6.2 Results

Test port	Voltage (rms)	Modulation Frequency	Frequency Range	Opinion
AC power line	3	1 kHz, 80%,AM	150 kHz - 80 MHz	А

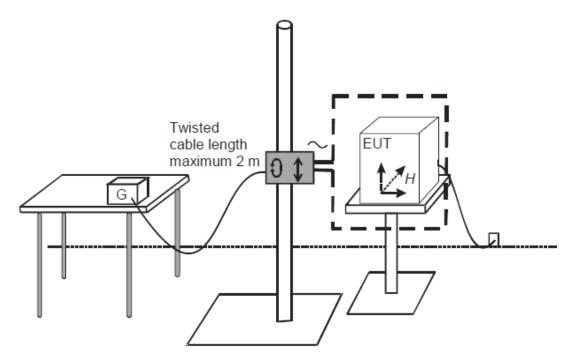
A: no loss of function.



# 5.7 **Power-frequency magnetic fields**

The magnetic fields to which equipment is subjected may influence the reliable operation of equipment and systems.

# 5.7.1 Measurement procedure



The electromagnetic conditions of the laboratory shall be such as to guarantee the correct operation of the EUT in order not to influence the test results; otherwise, the tests shall be carried out in a Faraday cage. The plane of the inductive coil shall then be rotated by 90° in order to expose the EUT to the test field with different orientations.

### 5.7.2 Results

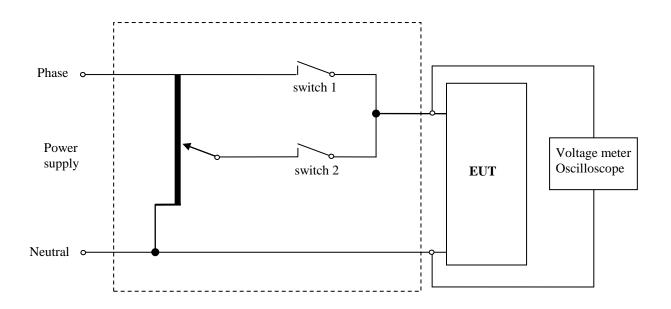
Test Frequency	Field Level (A/m)	Duration (Second)	Axis of Orientation	Opinion
50/60Hz	1	60	Х	A
50/60Hz	1	60	Y	А
50/60Hz	1	60	Z	A

A: no loss of function.



# **5.8** Voltage dips and Interruption

# 5.8.1 Measurement procedure



- 1. The EUT was placed on a ground reference plane(GRP) insulated by an insulating support 0,1 m thick and the GRP was placed on a 0.8m high wooden table for table-top equipment. For floor standing equipment, the EUT was placed on a 0.1m high wooden support above the GRP.
- 2. The test was performed with the EUT connected to the test generator with the shortest power supply cable as specified by the EUT manufacturer. Voltage change shall occur at zero crossing.
- 3. The EUT was tested for each selected combination of test level and duration with a sequence of three dips /interruptions with intervals of 10 s minimum. Each representative mode of operation was tested.

# 5.8.2 Results

Supply voltage	Voltage in % (in V)	Duration in parts of period (in ms)	Opinion
Voltage dips	0 % (0V)	0,5 (10 ms)	А
Voltage dips	70 %(161V)	25 (500 ms)	А
Voltage interruptions	0 % (0 V)	250 (5000 ms)	А

A: no loss of function.



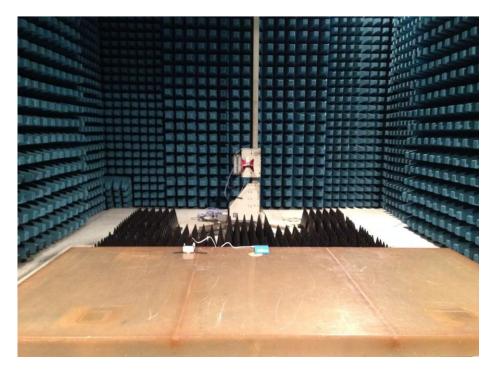
# 6 Test setup Photos

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Radiated disturbance Above 1G



Voltage Changes, Voltage Fluctuations and Flicker





# **Electrostatic Discharge**

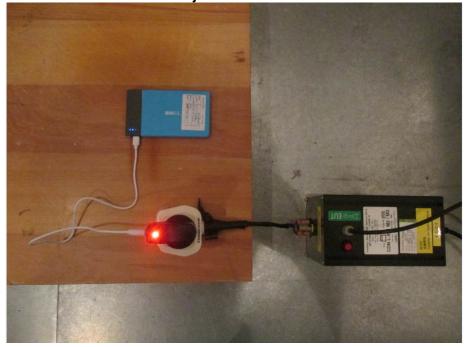


Radio frequency electromagnetic fields





Injected currents



# Power-frequency magnetic fields





# Surge EFT and Voltage dips and Interruption





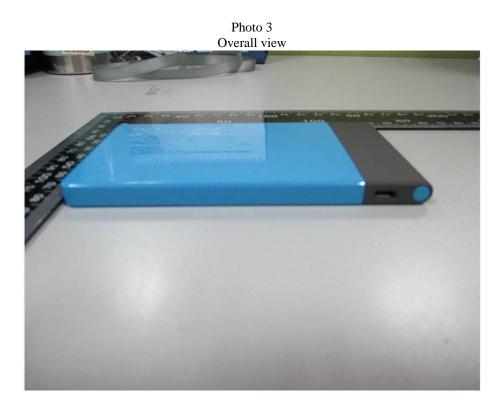
# 7 EUT Photos

Photo 1 Overall view do 70 do 90 100 to 20 30 40 50 do 70 do 90 20 30 40 50 40 30 20 100 70 | 80 | 90 | | 10 | 20 | 30 | 40 | | 60 | 7 50 0 10 80 70 60 50 40 0 40 30 20 10 90<sup>8</sup> 1<sup>0</sup> 100 8 20 8|0 90 30 100 40 #30 #40 **#**90 50 60 5 | 20 | 916.90 30 surforus 😪 2 40 0

#### Photo 2 Overall view







#### Photo 4 Overall view





# Photo 5



#### Photo 6 PCB view





Photo 7 PCB view

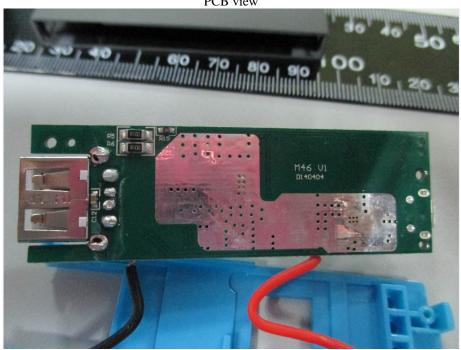


Photo 8 Cable view





Photo 9

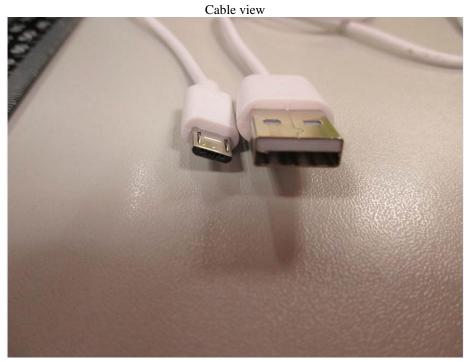


Photo 10 Overall view

